

Docket No.: 071971-0361

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of	:	Customer Number: 20277
Junko IWANAGA, et al.	:	Confirmation Number: Not yet
assigned	:	
Application No.: Not yet assigned	:	Group Art Unit: Not yet assigned
Filed: September 16, 2005	:	Examiner: Not yet assigned
For: SEMICONDUCTOR DEVICE AND METHOD FOR FABRICATING THE SAME	:	

INFORMATION DISCLOSURE STATEMENT

Honorable Commissioner for Patents and Trademarks
Washington, D. C. 20231

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached form PTO-1449. It is respectfully requested that the references be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed with the application and no certification or fee is required.

A copy of the foreign search report is attached for the Examiner's information. Please note this is a PCT application in the entry of the National Phase in the U.S. and copies of the references cited were transmitted by WIPO and are believed to be in the file of the above identified application and readily available to the Examiner. Therefore it is

Not yet assigned

10/549291

JC17 Rec'd PCT/PTO 16 SEP 2005

believed that Applicants have met all requirements regarding duty of disclosure under 37 CFR 1.56. Acknowledgement and consideration of these documents are respectfully requested.

A copy of the foreign search report is attached for the Examiner's information. Please note this is a PCT application in the entry of the National Phase in the U.S. Since the Search Report was from the U.S. JPO or EPO search authorities, copies of these references should have been supplied to the USPTO under the trilateral agreement and are believed to be in the file of the above identified application and readily available to the Examiner.

Respectfully submitted,

McDERMOTT WILL & EMERY LLP

Michael E. Fogarty
Registration No. 36,139

**Please recognize our Customer No. 20277
as our correspondence address.**

600 13th Street, N.W.
Washington, DC 20005-3096
Phone: 202.756.8000 MEF:aph
Facsimile: 202.756.8087
Date: September 16, 2005

INFORMATION DISCLOSURE CITATION IN AN APPLICATION						ATTY. DOCKET NO. 071971-0361		SERIAL NO. Not yet assigned 10/549291		
						APPLICANT Junko IWANAGA, et al.				
(PTO-1449)						FILING DATE September 16, 2005		GROUP Not yet assigned		
U.S. PATENT DOCUMENTS										
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ₂ (<i>if known</i>)		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document			Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
		US	4,996,574	2-26-1991	Shirasaki					
		US	2002/003256 A1	1-10-2002	Maegawa					
		US	6,288,431 B1	9-11-2001	Iwasa					
		US	6,413,802 B1	7-2-2002	Hu et al					
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FOREIGN PATENT DOCUMENTS										
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes -Number 4 -Kind Codes (<i>if known</i>)		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document		Pages, Columns, Lines Where Relevant Figures Appear		Translation Yes No	
		EP 0 623 963		11-9-1994	SIEMENS AG					
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)										
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.								
		KEDZIERSKI et al., "High-Performance Symmetric-Gate and CMOS-Compatible Vt Asymmetric-Gate FinFET Devices", International Electron Devices Meeting 2001, IEDM Technical Digest. Washington DC, Dec. 2-5, 2001, New York, NY: IEEE, pp1951-1954, XP010575161								
EXAMINER					DATE CONSIDERED					

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.